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April 1988 Revised August 1999

74F433

First-In First-Out (FIFO) Buffer Memory

General Description

The 74F433 is an expandable fall-through type high-speed First-In First-Out (FIFO) Buffer Memory that is optimized for high-speed disk or tape controller and communication buffer applications. It is organized as 64-words by 4-bits and may be expanded to any number of words or any number of bits in multiples of four. Data may be entered or extracted asynchronously in serial or parallel, allowing economical implementation of buffer memories.

The 74F433 has 3-STATE outputs that provide added versatility, and is fully compatible with all TTL families.

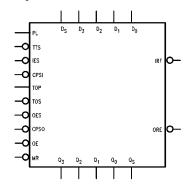
Features

- Serial or parallel input
- Serial or parallel output
- Expandable without additional logic
- 3-STATE outputs
- Fully compatible with all TTL families
- Slim 24-pin package
- 9423 replacement

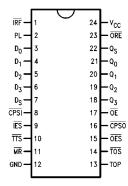
Ordering Code:

	Order Number	Package Number	Package Description
l	74F433SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide

Logic Symbol



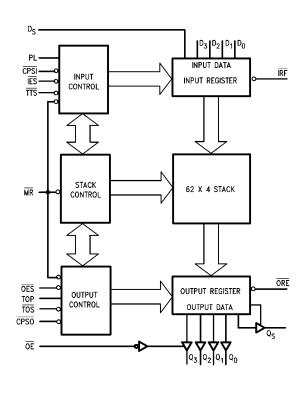
Connection Diagram



Unit Loading/Fan Out

Dia Namas	Description	U.L.	Input I _{IH} /I _{IL}	
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}	
PL	Parallel Load Input	1.0/0.66	20 μΑ/400 μΑ	
CPSI	Serial Input Clock	1.0/0.66	20 μΑ/400 μΑ	
ĪES	Serial Input Enable	1.0/0.66	20 μΑ/400 μΑ	
TTS	Transfer to Stack Input	1.0/0.66	20 μΑ/400 μΑ	
MR	Master Reset	1.0/0.66	20 μΑ/400 μΑ	
OES	Serial Output Enable	1.0/0.66	20 μΑ/400 μΑ	
TOP	Transfer Out Parallel	1.0/0.66	20 μΑ/400 μΑ	
TOS	Transfer Out Serial	1.0/0.66	20 μΑ/400 μΑ	
CPSO	Serial Output Clock	1.0/0.66	20 μΑ/400 μΑ	
ŌĒ	Output Enable	1.0/0.66	20 μΑ/400 μΑ	
D ₀ –D ₃	Parallel Data Inputs	1.0/0.66	20 μΑ/400 μΑ	
D_S	Serial Data Input	1.0/0.66	20 μΑ/400 μΑ	
Q ₀ -Q ₃	Parallel Data Outputs	285/10	5.7 mA/16 mA	
Q_S	Serial Data Output	285/10	5.7 μA/16 mA	
ĪRF	Input Register Full	20/5	400 μA/8 mA	
ORE	Output Register Empty	20/5	400 μA/8 mA	

Block Diagram



Functional Description

As shown in the block diagram, the 74F433 consists of three sections:

- 1. An Input Register with parallel and serial data inputs, as well as control inputs and outputs for input handshaking and expansion.
- 2. A 4-bit-wide, 62-word-deep fall-through stack with selfcontained control logic.
- 3. An Output Register with parallel and serial data outputs, as well as control inputs and outputs for output handshaking and expansion.

These three sections operate asynchronously and are virtually independent of one another.

Input Register (Data Entry)

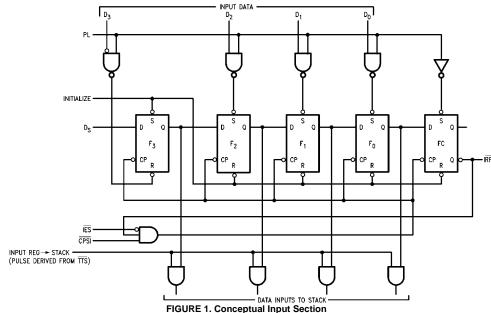
The Input Register can receive data in either bit-serial or 4bit parallel form. It stores this data until it is sent to the fallthrough stack, and also generates the necessary status and control signals.

This 5-bit register (see Figure 1) is initialized by setting flipflop F₃ and resetting the other flip-flops. The Q-output of the last flip-flop (FC) is brought out as the Input Register Full (IRF) signal. After initialization, this output is HIGH.

Parallel Entry-A HIGH on the Parallel Load (PL) input loads the $\mathrm{D_0-D_3}$ inputs into the $\mathrm{F_0-F_3}$ flip-flops and sets the FC flip-flop. This forces the IRF output LOW, indicating that the input register is full. During parallel entry, the Serial Input Clock (CPSI) input must be LOW.

Serial Entry—Data on the Serial Data (D_S) input is serially entered into the shift register (F $_3$, F $_2$, F $_1$, F $_0$, FC) on each HIGH-to-LOW transition of the CPSI input when the Serial Input Enable (IES) signal is LOW. During serial entry, the PL input should be LOW.

After the fourth clock transition, the four data bits are located in flip-flops $\mathsf{F}_0\text{--}\mathsf{F}_3.$ The FC flip-flop is set, forcing the IRF output LOW and internally inhibiting CPSI pulses from affecting the register. Figure 2 illustrates the final positions in an 74F433 resulting from a 256-bit serial bit train (B₀ is the first bit, B₂₅₅ the last).



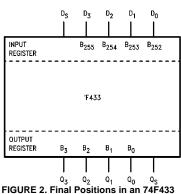


FIGURE 2. Final Positions in an 74F433 Resulting from a 256-Bit Serial Train

Fall-Through Stack—The outputs of flip-flops F₀-F₃ feed the stack. A LOW level on the Transfer to Stack (TTS) input initiates a fall-through action; if the top location of the stack is empty, data is loaded into the stack and the input register is re-initialized. (Note that this initialization is delayed until PL is LOW). Thus, automatic FIFO action is achieved by connecting the IRF output to the TTS input.

An RS-type flip-flop (the initialization flip-flop) in the control section records the fact that data has been transferred to the stack. This prevents multiple entry of the same word into the stack even though $\overline{\text{IRF}}$ and $\overline{\text{TTS}}$ may still be LOW; the initialization flip-flop is not cleared until PL goes LOW.

Once in the stack, data falls through automatically, pausing only when it is necessary to wait for an empty next location. In the 74F433, the master reset (MR) input only initializes the stack control section and does not clear the data.

Output Register

The Output Register (see Figure 3) receives 4-bit data words from the bottom stack location, stores them, and outputs data on a 3-STATE, 4-bit parallel data bus or on a 3-STATE serial data bus. The output section generates and receives the necessary status and control signals.

Parallel Extraction—When the FIFO is empty after a LOW pulse is applied to the MR input, the Output Register Empty (ORE) output is LOW. After data has been entered into the FIFO and has fallen through to the bottom stack location, it is transferred into the output register, if the Transfer Out Parallel (TOP) input is HIGH. As a result of the data transfer, ORE goes HIGH, indicating valid data on the data outputs (provided that the 3-STATE buffer is enabled). The TOP input can then be used to clock out the next word.

When TOP goes LOW, ORE also goes LOW, indicating that the output data has been extracted; however, the data itself remains on the output bus until a HIGH level on TOP permits the transfer of the next word (if available) into the output register. During parallel data extraction, the serial output clock (CPSO) line should be LOW. The Transfer Out Serial (TOS) line should be grounded for single-slice operation or connected to the appropriate ORE line for expanded operation (refer to the "Expansion" section).

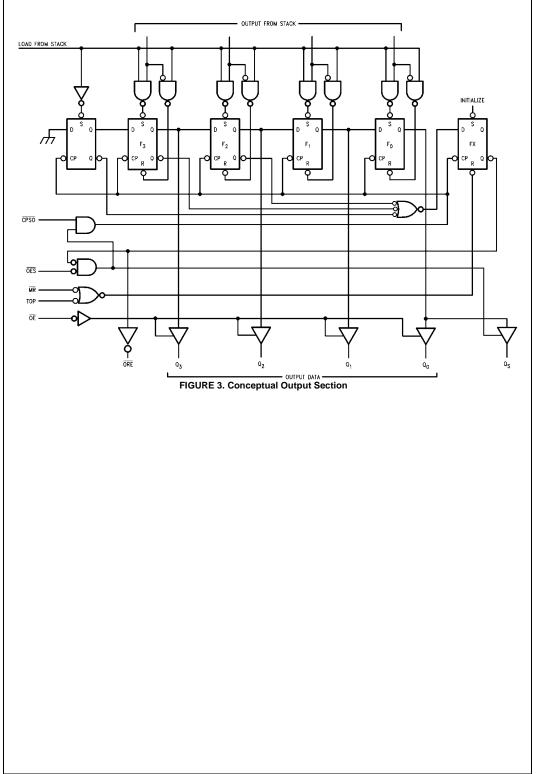
The TOP signal is not edge-triggered. Therefore, if TOP goes HIGH before data is available from the stack but data becomes available before TOP again goes LOW, that data is transferred into the output register. However, internal control circuitry prevents the same data from being transferred twice. If TOP goes HIGH and returns to LOW before data is available from the stack, ORE remains LOW, indicating that there is no valid data at the outputs.

Serial Extraction-When the FIFO is empty after a LOW is applied to the MR input, the ORE output is LOW. After data has been entered into the FIFO and has fallen through to the bottom stack location, it is transferred into the output register, if the TOS input is LOW and TOP is HIGH. As a result of the data transfer, ORE goes HIGH, indicating that valid data is in the register.

The 3-STATE Serial Data Output (Q_S) is automatically enabled and puts the first data bit on the output bus. Data is serially shifted out on the HIGH-to-LOW transition of CPSO. To prevent false shifting, CPSO should be LOW when the new word is being loaded into the output register. The fourth transition empties the shift register, forces ORE LOW, and disables the serial output, QS. For serial operation, the ORE output may be tied to the TOS input, requesting a new word from the stack as soon as the previous one has been shifted out.

Expansion

Vertical Expansion—The 74F433 may be vertically expanded, without external components, to store more words. The interconnections necessary to form a 190-word by 4-bit FIFO are shown in Figure 4. Using the same technique, any FIFO of (63n+1)-words by 4-bits can be configured, where n is the number of devices. Note that expansion does not sacrifice any of the 74F433 flexibility for serial/parallel input and output.



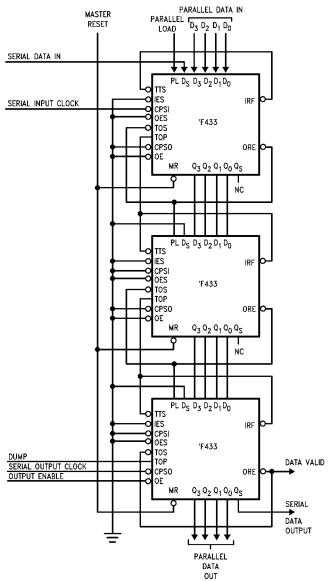


FIGURE 4. A Vertical Expansion Scheme

Horizontal Expansion—The 74F433 can be horizontally expanded, without external logic, to store long words (in multiples of 4-bits). The interconnections necessary to form a 64-word by 12-bit FIFO are shown in Figure 5. Using the same technique, any FIFO of 64-words by 4n-bits can be constructed, where n is the number of devices.

The right-most (most significant) device is connected to the TTS inputs of all devices. Similarly, the ORE output of the most significant device is connected to the TOS inputs of all devices. As in the vertical expansion scheme, horizontal expansion does not sacrifice any of the 74F433 flexibility for serial/parallel input and output.

It should be noted that the horizontal expansion scheme shown in Figure 5 exacts a penalty in speed.

Horizontal and Vertical Expansion—The 74F433 can be expanded in both the horizontal and vertical directions without any external components and without sacrificing any of its FIFO flexibility for serial/parallel input and output. The interconnections necessary to form a 127-word by 16-bit FIFO are shown in Figure 6. Using the same technique, any FIFO of (63m+1)-words by 4n-bits can be configured, where m is the number of devices in a column and n is the number of devices in a row. Figure 7 and Figure 8 illustrate the timing diagrams for serial data entry and extraction for the FIFO shown in Figure 6. Figure 9 illustrates the final

positions of bits in an expanded 74F433 FIFO resulting from a 2032-bit serial bit train.

Interlocking Circuitry—Most conventional FIFO designs provide status signal analogous to IRF and ORE. However, when these devices are operated in arrays, variations in unit-to-unit operating speed require external gating to ensure that all devices have completed an operation. The 74F433 incorporates simple but effective 'master/slave' interlocking circuitry to eliminate the need for external gating

In the 74F433 array of Figure 6, devices 1 and 5 are the row masters; the other devices are slaves to the master in their rows. No slave in a given row initializes its input register until it has received a LOW on its IES input from a row master or a slave of higher priority.

Similarly, the $\overline{\text{ORE}}$ outputs of slaves do not go HIGH until their inputs have gone HIGH. This interlocking scheme ensures that new input data may be accepted by the array when the $\overline{\text{IRF}}$ output of the final slave in that row goes HIGH and that output data for the array may be extracted when the $\overline{\text{ORE}}$ output of the final slave in the output row goes HIGH.

The row master is established by connecting its $\overline{\text{IES}}$ input to ground, while a slave receives its $\overline{\text{IES}}$ input from the $\overline{\text{IRF}}$ output of the next-higher priority device. When an array of 74F433 FIFOs is initialized with a HIGH on the MR inputs of all devices, the $\overline{\text{IRF}}$ outputs of all devices are HIGH. Thus, only the row master receives a LOW on the $\overline{\text{IES}}$ input during initialization.

Figure 10 is a conceptual logic diagram of the internal circuitry that determines master/slave operation. When $\overline{\text{MR}}$ and IES are LOW, the master latch is set. When $\overline{\text{TTS}}$ goes LOW, the initialization flip-flop is set. If the master latch is HIGH, the input register is immediately initialized and the initialization flip-flop reset. If the master latch is reset, the input register is not initialized until IES goes LOW. In array operation, activating $\overline{\text{TTS}}$ initiates a ripple input register initialization from the row master to the last slave.

A similar operation takes place for the output register. Either a TOS or TOP input initiates a load-from-stack operation and sets the ORE request flip-flop. If the master latch is set, the last output register flip-flop is set and the ORE line goes HIGH. If the master latch is reset, the ORE output is LOW until a Serial Output Enable (OES) input is received.

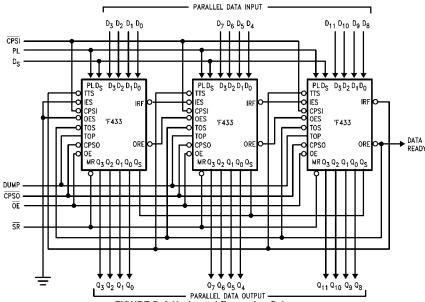
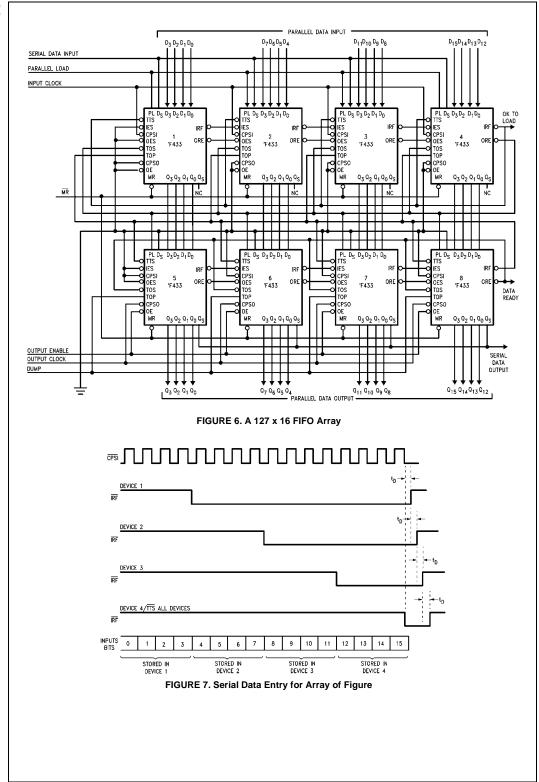
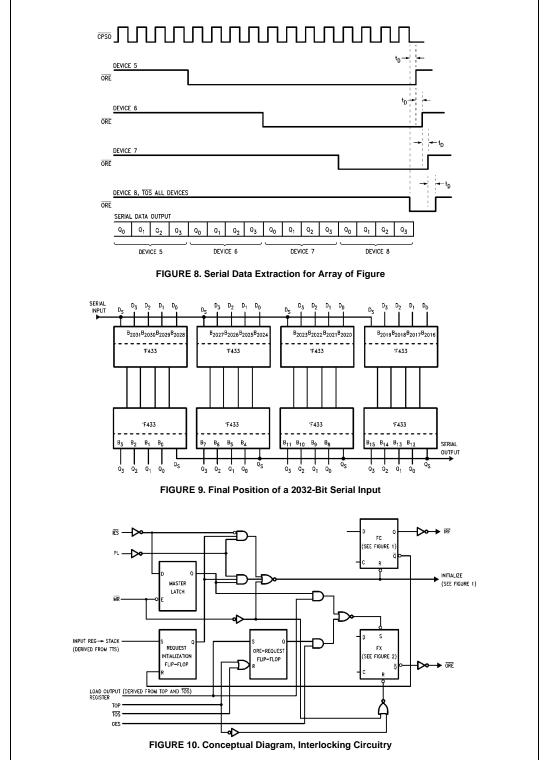


FIGURE 5. A Horizontal Expansion Scheme





Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

Storage Temperature -65°C to +150°C

Ambient Temperature under Bias -55°C to $+125^{\circ}\text{C}$ Junction Temperature under Bias -55°C to $+150^{\circ}\text{C}$

V_{CC} Pin Potential to

 $\begin{array}{lll} \mbox{Ground Pin} & -0.5\mbox{V to } +7.0\mbox{V} \\ \mbox{Input Voltage (Note 2)} & -0.5\mbox{V to } +7.0\mbox{V} \\ \mbox{Input Current (Note 2)} & -30\mbox{ mA to } +5.0\mbox{ mA} \\ \end{array}$

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

 $\begin{array}{lll} \text{Standard Output} & & -0.5 \text{V to V}_{\text{CC}} \\ \text{3-STATE Output} & & -0.5 \text{V to +5.5V} \end{array}$

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Free Air Ambient Temperature $0^{\circ}\text{C to } +70^{\circ}\text{C}$ Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

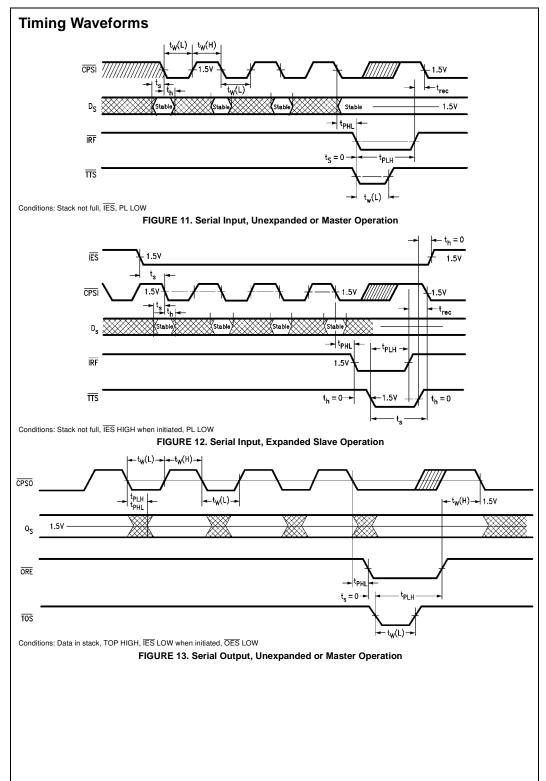
Symbol	Parameter		Min	Тур	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.5	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH	10% V _{CC}	2.4					$I_{OH} = 400 \mu A (\overline{ORE}, \overline{IRF})$
	Voltage	10% V _{CC}	2.4			v	Min	$I_{OH} = 5.7 \text{ mA } (Q_n, Q_s)$
		5% V _{CC}	2.7			V	IVIIN	$I_{OH} = 400 \mu A (\overline{ORE}, \overline{IRF})$
		5% V _{CC}	2.7					$I_{OH} = 5.7 \text{ mA } (Q_n, Q_s)$
V _{OL}	Output LOW Voltage	10% V _{CC}			0.50	V	Min	$I_{OL} = 16 \text{ mA } (Q_n, Q_s)$
I _{IH}	Input HIGH Current				5.0	μΑ	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current				7.0	μА	Max	V _{IN} = 7.0V
	Breakdown Test				7.0	μΛ	IVIAX	
I _{CEX}	Output HIGH				50	μА	Max	$V_{OUT} = V_{CC}$
	Leakage Current				00	po t	max	
V _{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$
	Test		4.75			•	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75	μА	0.0	V _{IOD} = 150 mV
	Circuit Current				0.75	μΛ	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.4	mA	Max	$V_{IN} = 0.5V$
I _{OZH}	Output Leakage Current				50	μΑ	Max	$V_{OUT} = 2.7V (Q_n, Q_s)$
I _{OZL}	Output Leakage Current				-50	μΑ	Max	$V_{OUT} = 0.5V (Q_n, Q_s)$
los	Output Short-Circuit Current		-20		-130	mA	Max	$V_{OUT} = 0V$
I _{CC}	Power Supply Current			150	215	mA	Max	

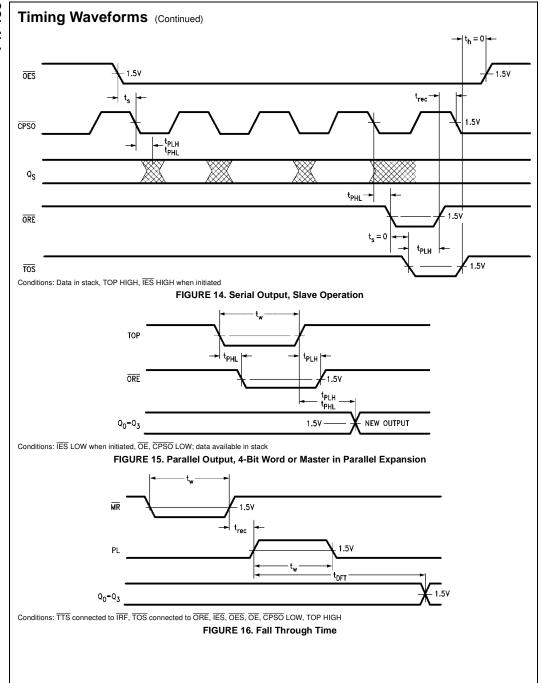
AC Electrical Characteristics

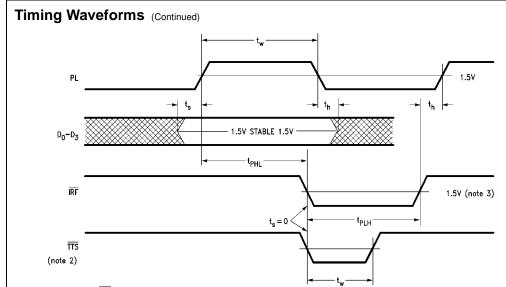
			+25°C	T _A = 0°C			
Symbol	Parameter	V _{CC} =		$V_{CC} = +5.0V$		Units	Figure Number
			C _L = 50 pF		50 pF		
		Min	Max	Min	Max		
t _{PHL}	Propagation Delay, Negative-Going	2.0	17.0	2.0	18.0		
	CPSI to IRF Output		-			ns	Figure 11
t _{PLH}	Propagation Delay,	9.0	34.0	8.0	38.0		Figure 12
	Negative-Going TTS to IRF						
t _{PLH}	Propagation Delay, Negative-Going	4.0	25.0	3.0	27.0	ns	Figure 13
t _{PHL}	CPSO to Q _S Output	5.0	20.0	5.0	21.0	113	Figure 14
t _{PLH}	Propagation Delay, Positive-Going	8.0	35.0	7.0	38.0	ns	Figure 15
t _{PHL}	TOP to Q ₀ –Q ₃ Outputs	7.0	30.0	7.0	32.0	115	rigule 13
t _{PHL}	Propagation Delay,	7.0	25.0	6.0	28.0		Figure 13
	Negative-Going CPSO to ORE	7.0	25.0	6.0	26.0	ns	Figure 14
t _{PHL}	Propagation Delay,						
	Negative-Going TOP to ORE	6.0	26.0	6.0	28.0		
t _{PLH}	Propagation Delay, Positive-Going					ns	Figure 15
	TOP to ORE	13.0	48.0	12.0	51.0		
t _{PLH}	Propagation Delay, Negative-Going						Figure 13
TLI	TOS to Positive-Going ORE	13.0	45.0	12.0	50.0	ns	Figure 14
t _{PHL}	Propagation Delay, Positive-						
PHL	Going PL to Negative-Going IRF	4.0	22.0	4.0	23.0		Figure 17 Figure 18
	Propagation Delay, Negative-					ns	
t _{PLH}		7.0	31.0	6.0	35.0		i iguio io
	Going PL to Positive-Going IRF						
t _{PLH}	Propagation Delay,	9.0	38.0	8.0	44.0	ns	
	Positive-Going OES to ORE						
t _{PLH}	Propagation Delay Positive-IRF	5.0	05.0	F 0	27.0		Figure 10
	Going IES to Positive-Going	5.0	25.0	5.0	27.0	ns	Figure 18
t _{PHL}	Propagation Delay						
	MR to ORE	7.0	28.0	7.0	31.0	ns	
t _{PLH}	Propagation Delay						
	MR to IRF	5.0	27.0	5.0	30.0	ns	
t _{PZH}	Enable Time	1.0	16.0	1.0	18.0		
	OE to Q ₀ -Q ₃	1.0	14.0	1.0	16.0		
t _{PZL}	Disable Time	1.0	10.0	1.0	12.0	ns	
t _{PHZ}	l	1.0	23.0	1.0	30.0		
t _{PLZ}	OE to Q ₀ –Q ₃	1.0	10.0	1.0	12.0		
t _{PZH}		_		-			
t _{PZL}	Negative-Going OES to Q _S	1.0	14.0	1.0	15.0	ns	
t _{PHZ}	Disable Time	1.0	10.0	1.0	12.0		
t _{PLZ}	Negative-Going OES to Q _S	1.0	14.0	1.0	16.0		
t _{PZH}	Enable Time	1.0	35.0	1.0	42.0	ns	
t _{PZL}	TOS to Q _S	1.0	35.0	1.0	39.0		
t _{DFT}	Fall-Through Time	0.2	0.9	0.2	1.0	ns	Figure 16
t _{AP}	Parallel Appearance Time	-20.0	-2.0	-20.0	-2.0		
	ORE to Q ₀ –Q ₃	-20.0	-2.0	-20.0	-2.0	no	
t _{AS}	Serial Appearance Time	-20.0	E 0	-20.0	E 0	ns	
	ORE to Q _S	-20.0	5.0	-20.0	5.0		

AC Operating Requirements

		T _A = +25°C		$T_A = 0$ °C to +70°C			Figure Number
Symbol	Parameter	V _{CC} =	$V_{CC} = +5.0V$		V _{CC} = +5.0V		
		Min	Max	Min	Max		Number
t _S (H)	Setup Time, HIGH or LOW	7.0		7.0			
t _S (L)	D _S to Negative CPSI	7.0		7.0			Figure 11 Figure 12
t _H (H)	Hold Time, HIGH or LOW	2.0		2.0		ns	
$t_{H}(L)$	D _S to CPSI	2.0		2.0			
t _S (L)	Setup Time, LOW TTS to IRF, Serial or Parallel Mode	0.0		0.0		ns	Figure 11 Figure 12 Figure 17 Figure 18
t _S (L)	Setup Time, LOW Negative-Going ORE to Negative-Going TOS	0.0		0.0		ns	Figure 13 Figure 14
t _S (L)	Setup Time, LOW Negative-Going IES to CPSI	8.0		9.0			Figure 12
t _S (L)	Setup Time, LOW Negative-Going TTS to CPSI	30.0		33.0		ns	
t _S (H)	Setup Time, HIGH or LOW	0.0		0.0		ns	
$t_S(L)$	Parallel Inputs to PL	0.0		0.0			
t _H (H)	Hold Time, HIGH or LOW	4.0		4.0			
t _H (L)	Parallel Inputs to PL	4.0		4.0			
$t_W(H)$	CPSI Pulse Width	10.0		11.0		ns	Figure 11
$t_{W}(L)$	HIGH or LOW	5.0		6.0		lis	Figure 12
t _W (H)	PL Pulse Width, HIGH	7.0		9.0		ns	Figure 17 Figure 18
t _W (L)	TTS Pulse Width, LOW Serial or Parallel Mode	7.0		9.0		ns	Figure 11 Figure 12 Figure 13 Figure 14
t _W (L)	MR Pulse Width, LOW	7.0		9.0		ns	Figure 16
t _W (H)	TOP Pulse Width	14.0		16.0		ns	Figure 15
$t_{W}(L)$	HIGH or LOW	7.0		7.0		115	Figure 15
t _W (H)	CPSO Pulse Width	14.0		16.0			Figure 13
$t_W(L)$	HIGH or LOW	7.0		7.0		ns	Figure 14
t _{REC}	Recovery Time MR to Any Input	8.0		15.0		ns	Figure 16





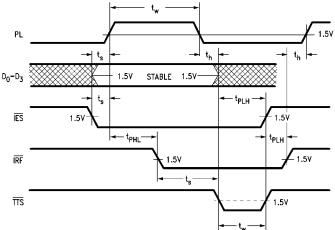


Conditions: Stack not full, $\overline{\rm IES}$ LOW when initialized

NOTE A: $\overline{\text{TTS}}$ normally connected to $\overline{\text{IRF}}$.

NOTE B: If stack is full, $\overline{\text{IRF}}$ will stay LOW.

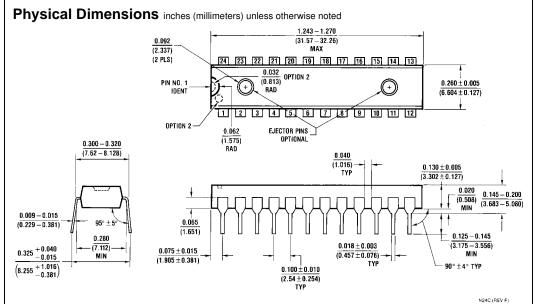
FIGURE 17. Parallel Load Mode, 4-Bit Word (Unexpanded) or Master in Parallel Expansion



Conditions: Stack not full, device initialized (Note 3) with $\overline{\text{IES}}\ \text{HIGH}$

Note 3: Initialization requires a master reset to occur after power has been applied.

FIGURE 18. Parallel Load, Slave Mode



24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300 Wide Package Number N24C

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- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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